Department of Physics

**Indian Institute of Technology Patna**

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**Requisition form for FESEM**

1. USER and PAYMENT DETAILS

|  |  |
| --- | --- |
| Name:Department:Contact No:e-mail ID: | **Estimated analytical charges:**(See the basic charges mentioned at the end of this form. Also, please see the terms and conditions, to know about any additional charges) |

1. SAMPLE DETAILS

|  |  |
| --- | --- |
| **No of Samples with sample ID (s):** |  |
| Nature of sample | Is the sample magnetic? If yes, mention magnetism value.Is the sample hygroscopic? Yes/NoWhether the sample is volatile? (Yes/No)Any other sample info relevant to FESEM… |

1. EXPERIMENTAL DETAILS REQUIRED

|  |
| --- |
| 1. Imaging mode: Secondary Electron (SE)/Back Scattered Electron (BSE)
2. Magnification Required:
3. Composition analysis of the sample:
	1. Qualitative microanalysis (EDS) Expected elements:
	2. X-ray mapping: Line scan/spot scan (mention spot size):
4. Any other specific requirement:
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Signature of the user

 Name & Signature of the Supervisor

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| --- |
| 1. **Payment from Department operating grant**: An amount of Rs ………. is sanctioned as the analytical charge towards the measurement with HRTEM. The said amount may be transferred on ledger from department of ……………………. to department of Physics.
2. **Payment from R&D project:** An amount of Rs ………. is sanctioned as the analytical charge towards the measurement with HRTEM. The said amount may be transferred on ledger from the project ……….……….to ledger of analytical charges in DDF of department of Physics at R&D, IIT Patna
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Signature of HoD, user department/Dean, R&D

**Terms and Conditions for using the Facilities**

1. The mentioned charges are **excluding any applicable GST.**
2. The charges mentioned are **per slot of one hour** unless otherwise mentioned in specific tables mentioning analytical charges. The slot time includes the sample loading time. The actual **number of samples** to be done in a slot **depends upon the specific requirement** of the user or the instrument feasibility. In case a single sample takes more than one 1 hr (may be due to nature of measurement or due to the specific requirement from user), the **total charges will be suitable integer multiplication of the charges for one slot**.
3. Samples should be ready to use for/in/with FESEM.
4. User may contact the concerned operator for the experiment specific preparation/treatment of sample.
5. The charges mentioned are only for measurement and providing the raw data (in the format possible with the instrument) thereafter. No analysis/software compatibility of data can be claimed later. For consultancy on data analysis, the user may contact the experts separately through head of the department.
6. Measurements are subject to the corresponding instrument being in working condition. The status of each instrumental facility will be updated regularly.
7. In case of the measurement remains incomplete due to malfunctioning or any unforeseen situation, the user will be notified. Depending upon user’s discretion, either the payment received will be returned or the measurement will be carried out after the instrument becomes functional (maximum waiting period also may be informed by user).

**Analytical charges related to experiments performed with Scanning Electron Microscopy**

|  |  |
| --- | --- |
| Name of the facility | Analytical charges (in INR, per hour)  |
| IIT Patna Users  | Users from external academic institutes | Users from Industries /R & D laboratories |
| Scanning Electron Microscopy (SEM) | 500 | 2000 | 4000(Additional 500 per sample, if Pt/Au coating is required) |

\*For any specific customized measurement/testing, the analytical charges can be estimated in consultation with Physics department.

FOR OFFICE USE ONLY

SLOT ALLOTMENT DETAILS

Date of submission of form:

Job Order Number:

Assigned date and time of execution: No. of slots allotted:

Signature of staff operator/in-charge

Signature of Faculty in-charge